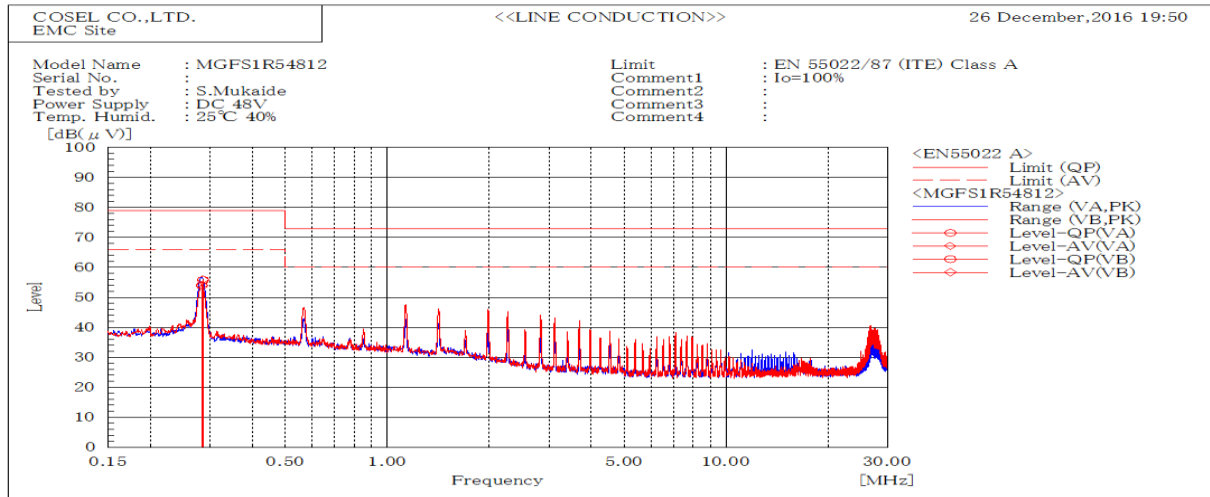
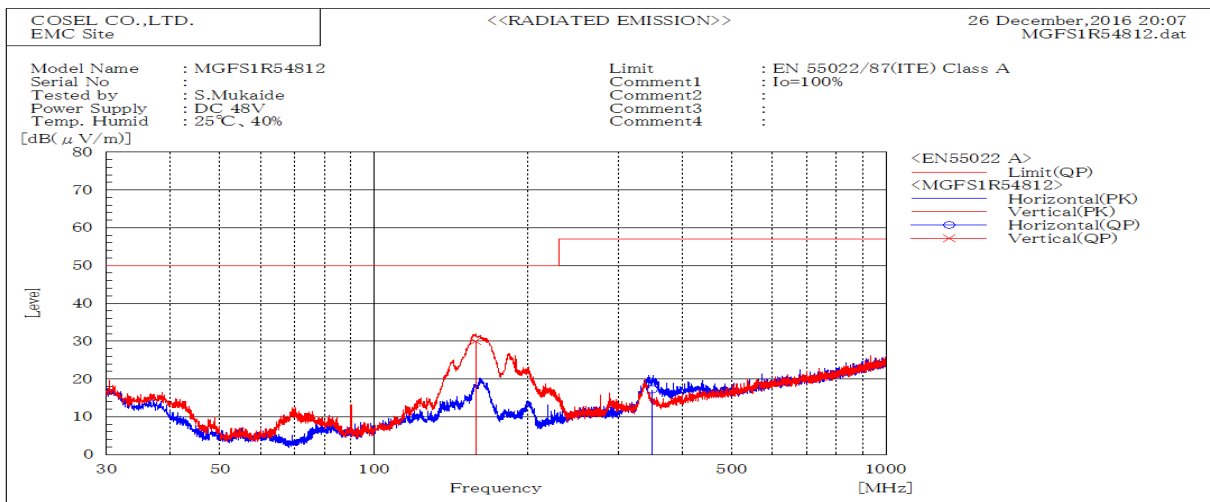


DATA SHEET		Date	06-Jan-17
Model	MGFS1R54812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Mukaide



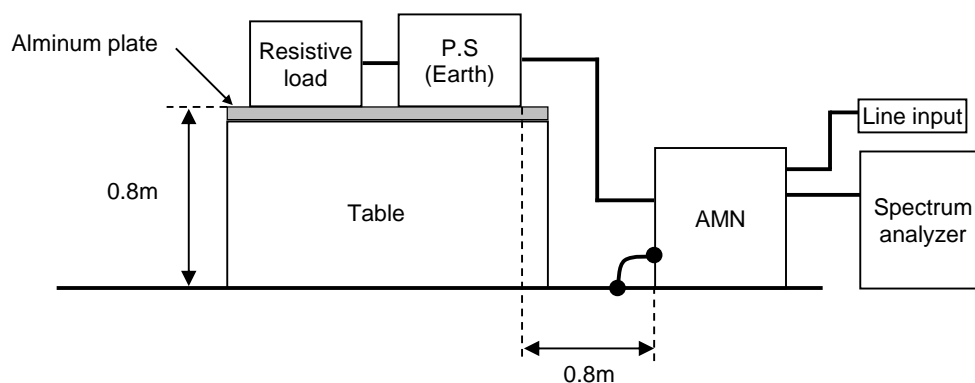
Frequency MHz	Line Phase	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.28356	VB	54	54	79	66	25	12	Pass	
0.28566	VA	55.8	56	79	66	23.2	10	Pass	



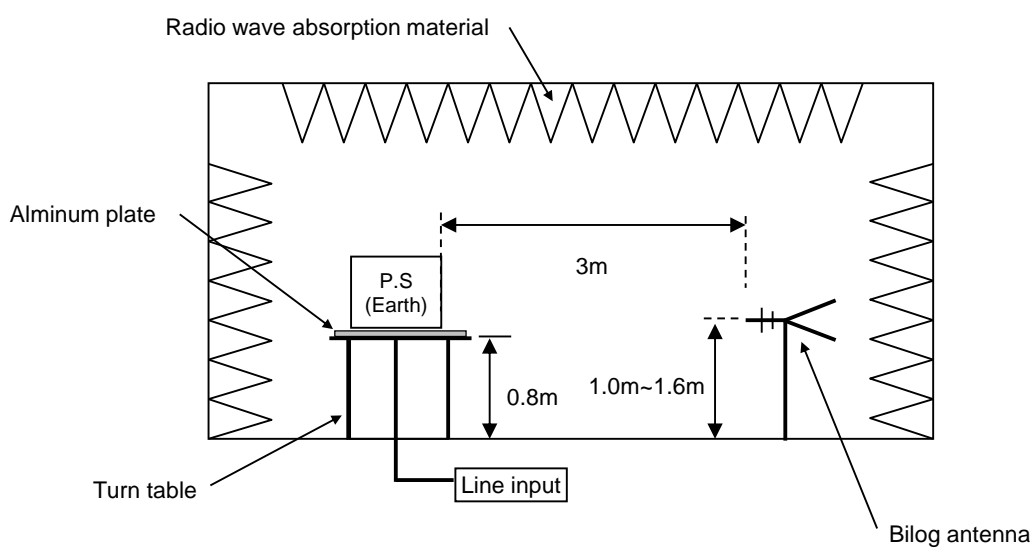
Frequency MHz	Polarization	Stability	Reading dB(μV)	Limit dB(μV/m)	Margin dB(μV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
157.840	V	Stable	30.0	50.0	20.0	Pass	109	11	
349.004	H	Stable	17.3	57.0	39.7	Pass	126	249	

DATA SHEET		Date	06-Jan-17
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Mukaide

1. Line conduction



2. Radiated emission

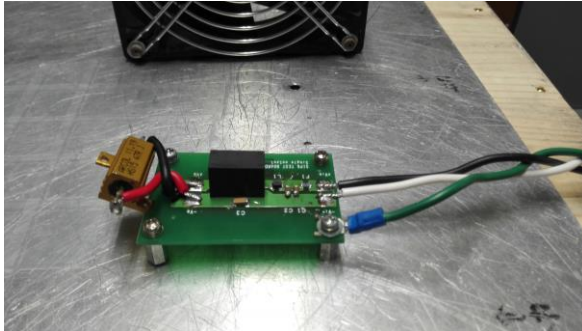


Conditions

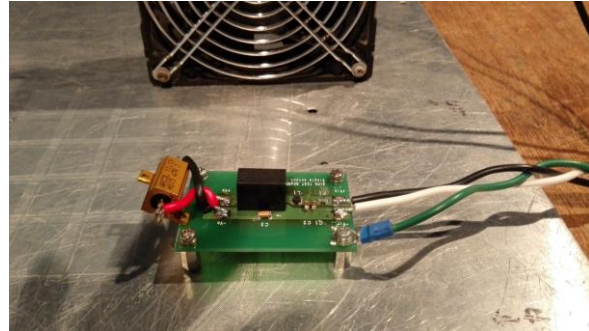
Test : EMI
Model Name : MGFS1R5□□

○Photographs of Test Set-Up

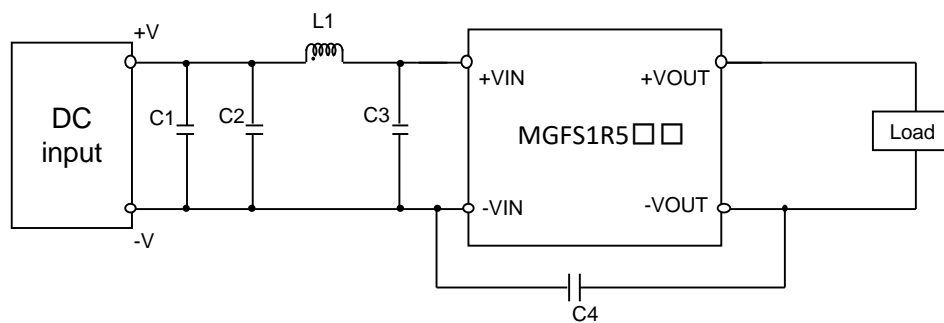
LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry



- | | | |
|------|-------------|--|
| C1 : | MGFS1R524□□ | 50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING) |
| | MGFS1R548□□ | 100V 2.2 μ F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING) |
| C2 : | MGFS1R524□□ | 50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING) |
| | MGFS1R548□□ | 100V 2.2 μ F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING) |
| C3 : | MGFS1R524□□ | 50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING) |
| | MGFS1R548□□ | 100V 2.2 μ F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING) |
| C4 : | MGFS1R524□□ | 2kV 470pF Ceramic capacitor (GR442QR73D471K MURATA MANUFACTURING) |
| | MGFS1R548□□ | 2kV 1000pF Ceramic capacitor (GR442QR73D102K MURATA MANUFACTURING) |
| L1 : | MGFS1R524□□ | 900mA 10 μ H Inductor(LQH32PN100MNCL MURATA MANUFACTURING) |
| | MGFS1R548□□ | 550mA 22 μ H Inductor(LQH32PN220MNCL MURATA MANUFACTURING) |